DS05-11150-1E

MEMORY Un-buffered

$8~\text{M} \times 64~\text{BIT}$ SYNCHRONOUS DYNAMIC RAM SO-DIMM

MB8508S064CH-100/-100L

144-pin, 2 Clock, 1-bank, based on 8 M × 8 Bit SDRAMs with SPD

■ DESCRIPTION

The Fujitsu MB8508S064CH is a fully decoded, CMOS Synchronous Dynamic Random Access Memory (SDRAM) Module consisting of eight MB81F64842C devices which organized as two banks of 8 M \times 8 bits and a 2K-bit serial EEPROM on a 144-pin glass-epoxy substrate.

The MB8508S064CH features a fully synchronous operation referenced to a positive edge clock whereby all operations are synchronized at a clock input which enables high performance and simple user interface coexistence.

The MB8508S064CH is optimized for those applications requiring high speed, high performance and large memory storage, and high density memory organizations.

This module is ideally suited for workstations, PCs, laser printers, and other applications where a simple interface is needed.

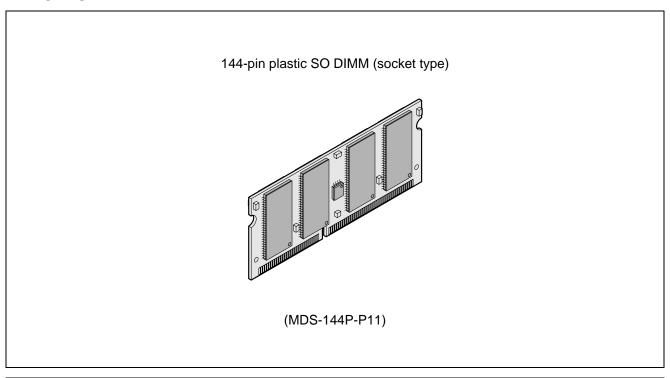
■ PRODUCT LINE & FEATURES

Dorometer	MB8508S064CH				
Parameter	-100	-100L			
Clock Frequency	100 MF	Hz max.			
Burst Mode Cycle Time	10 ns	s min.			
Access Time from Clock	8.5 ns ma:	x. (CL = 3)			
Operating Current	680 m	A max.			
Power Down Mode Current (Icc2P)	16 mA max.	8 mA max.			
Self Refresh Current (Icc6)	8 mA max.	4 mA max.			

- Unbuffered 144-pin SO-DIMM Socket Type (Lead pitch: 0.8 mm)
- Conformed to JEDEC Standard (2 CLK)
- Organization: 8,388,608 words × 64 bits
- Memory: MB81F64842C (8 M × 8, 4-bank) × 8 pcs.
- 3.3 V ±0.3 V Supply Voltage
- All input/output LVTTL compatible
- 4096 Refresh Cycle every 65.6 ms

- · Auto and Self Refresh
- CKE Power Down Mode
- DQM Byte Masking (Read/Write)
- Serial Presence Detect (SPD) with Serial EEPROM: JEDEC Standard SPD Format
- Module size:
 - 1.1" (height) \times 2.66" (length) \times 0.15" (thickness)
- CL-trcd-trp: 3-3-3 clk min. @100 MHz, 2-2-2 clk min. @66 MHz

■ PACKAGE

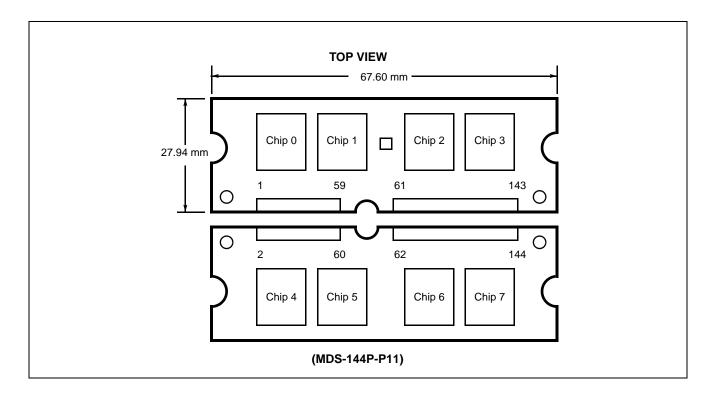


Package and Ordering Information

- 144-pin SO-DIMM, order as $\,$ MB8508S064CH-100DG (DG = Gold Pad) $\,$ MB8508S064CH-100LDG (LDG = Low power ver., Gold Pad)

■ PIN ASSIGNMENTS

Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name	Pin No.	Signal Name
1	Vss	49	DQ ₁₃	97	DQ22	2	Vss	50	DQ ₄₅	98	DQ ₅₄
3	DQ ₀	51	DQ ₁₄	99	DQ ₂₃	4	DQ ₃₂	52	DQ ₄₆	100	DQ ₅₅
5	DQ ₁	53	DQ ₁₅	101	Vcc	6	DQ33	54	DQ ₄₇	102	Vcc
7	DQ ₂	55	Vss	103	A 6	8	DQ ₃₄	56	Vss	104	A ₇
9	DQ ₃	57	N.C.	105	A8	10	DQ ₃₅	58	N.C.	106	BA ₀
11	Vcc	59	N.C.	107	Vss	12	Vcc	60	N.C.	108	Vss
13	DQ ₄	61	CLK ₀	109	A 9	14	DQ ₃₆	62	CKE ₀	110	BA ₁
15	DQ ₅	63	Vcc	111	A ₁₀	16	DQ ₃₇	64	Vcc	112	A ₁₁
17	DQ ₆	65	RAS	113	Vcc	18	DQ ₃₈	66	CAS	114	Vcc
19	DQ ₇	67	WE	115	DQMB ₂	20	DQ39	68	N.C.	116	DQMB ₆
21	Vss	69	CS ₀	117	DQMB ₃	22	Vss	70	N.C.	118	DQMB ₇
23	DQMB ₀	71	N.C.	119	Vss	24	DQMB ₄	72	N.C.	120	Vss
25	DQMB ₁	73	N.C.	121	DQ ₂₄	26	DQMB ₅	74	CLK ₁	122	DQ ₅₆
27	Vcc	75	Vss	123	DQ ₂₅	28	Vcc	76	Vss	124	DQ ₅₇
29	A ₀	77	N.C.	125	DQ ₂₆	30	Аз	78	N.C.	126	DQ ₅₈
31	A ₁	79	N.C.	127	DQ ₂₇	32	A ₄	80	N.C.	128	DQ ₅₉
33	A ₂	81	Vcc	129	Vcc	34	A 5	82	Vcc	130	Vcc
35	Vss	83	DQ ₁₆	131	DQ ₂₈	36	Vss	84	DQ ₄₈	132	DQ ₆₀
37	DQ ₈	85	DQ ₁₇	133	DQ ₂₉	38	DQ ₄₀	86	DQ ₄₉	134	DQ ₆₁
39	DQ ₉	87	DQ ₁₈	135	DQ ₃₀	40	DQ ₄₁	88	DQ50	136	DQ ₆₂
41	DQ ₁₀	89	DQ ₁₉	137	DQ ₃₁	42	DQ ₄₂	90	DQ ₅₁	138	DQ ₆₃
43	DQ ₁₁	91	Vss	139	Vss	44	DQ ₄₃	92	Vss	140	Vss
45	Vcc	93	DQ ₂₀	141	SDA	46	Vcc	94	DQ ₅₂	142	SCL
47	DQ ₁₂	95	DQ ₂₁	143	Vcc	48	DQ ₄₄	96	DQ ₅₃	144	Vcc



■ PIN DESCRIPTIONS

Symbol	I/O	Function	Symbol	I/O	Function
A ₀ to A ₁₁	I	Address Input	CS₀	I	Chip Select
BAo, BA1	I	Bank Address	DQ ₀ to DQ ₆₃	I/O	Data Input/Data Output
RAS	I	Row Address Strobe	Vcc		Power Supply (+3.3 V)
CAS	I	Column Address Strobe	Vss		Ground (0 V)
WE	I	Write Enable	N.C.		No Connection
DQMB ₀ to DQMB ₇	I	Data (DQ) Mask	SCL	I	Serial PD Clock
CLKo, CLK1	I	Clock Input	SDA	I/O	Serial PD Address/Data
CKE ₀	I	Clock Enable	SDA	1/0	Input/Output

■ SERIAL-PD INFORMATION

Byte	Function Described		Hex Value
Dyte	i unction Described		-100/100L
0	Defines Number of Bytes Written into Serial Memory at Module Manufacture	128 Byte	80h
1	Total Number of Bytes of SPD Memory Device	256 Byte	08h
2	Fundamental Memory Type	SDRAM	04h
3	Number of Row Addresses	12	0Ch
4	Number of Column Addresses	9	09h
5	Number of Module Banks	1 bank	01h
6	Data Width	64 bit	40h
7	Data Width (Continuation)	+0	00h
8	Interface Type	LVTTL	01h
9	SDRAM Cycle Time (Highest CAS Latency)	10 ns	A0h
10	SDRAM Access from Clock (Highest CAS Latency)	8.5 ns	85h
11	DIMM Configuration Type	Non-Parity	00h
12	Refresh Rate/Type	Self, Normal	80h
13	Primary SDRAM Width	×8	08h
14	Error Checking SDRAM Width	0	00h
15	Minimum Clock Delay for Back to Back Random Column Addresses	1 Cycle	01h
16	Burst Lengths Supported	1, 2, 4, 8, Page	8Fh
17	Number of Banks on Each SDRAM Device	4 bank	04h
18	CAS Latency	2, 3	06h
19	CS Latency	0	01h
20	Write Latency	0	01h
21	SDRAM Module Attributes	UN-buffer	00h
22	SDRAM Device Attributes	*1	0Eh
23	SDRAM Cycle Time (2nd. Highest CAS Latency)	15 ns	F0h
24	SDRAM Access from Clock (2nd. Highest CAS Latency)	9 ns	90h
25	SDRAM Cycle Time (3rd. Highest CAS Latency)	No Support	00h
26	SDRAM Access from Clock (3rd. Highest CAS Latency)	No Support	00h
27	Precharge to Activate Min. (trp)	30 ns	1Eh
28	Row Activate to Row Activate Min. (trrd)	20 ns	14h
29	RAS to CAS Delay Min. (trcd)	30 ns	1Eh
30	Activate to Precharge Minimum Time (tras)	60 ns	3Ch
31	Module Bank Density	64 MByte	10h
32 to 61	Unused Storage Locations	_	00h
62	SPD Data Revision Code	1	01h
63	Checksum for Byte 0 to 62	*2	57h
64 to 98	Manufacturer's Information: Unused Storage	_	00h
99 to 125	Vendor Specific Data: Unused Storage	_	00h
126	Intel Specification Frequency	66 MHz	66h
127	Intel Specification Details for 66 MHz Support	CL=2, 3	CFh
128+	Unused Storage Locations	<u> </u>	

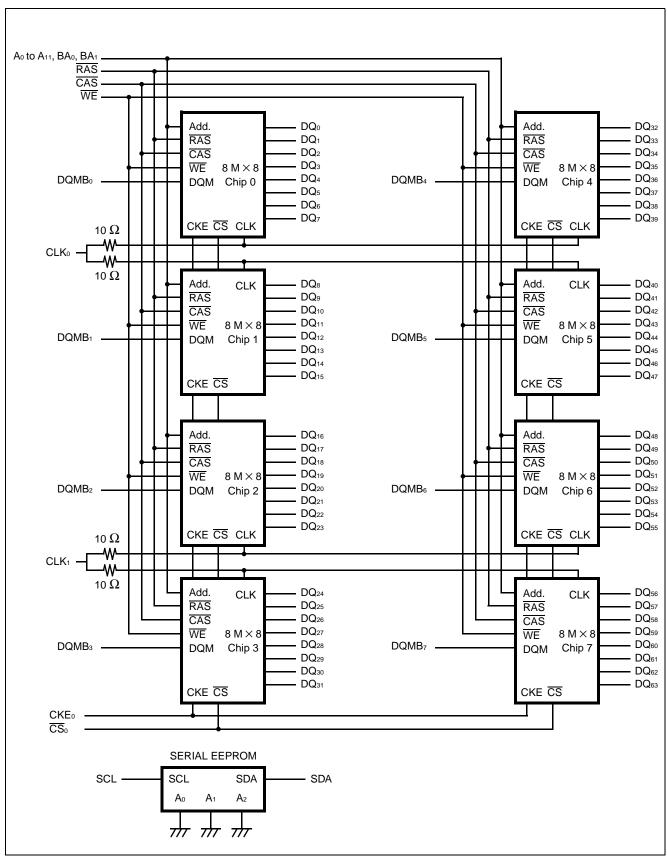
Note: Any write operation must NOT be executed into the addresses of Byte 0 to Byte 127. Some or all data stored into Byte 0 to Byte 127 may be broken.

*1. SDRAM Device Attributes

Bit7	Bit6	Bit5	Bit4	Bit3	Bit2	Bit1	Bit0
TBD	TBD	Upper Vcc tolerance 0 = 10%	Lower Vcc tolerance 0 = 10%	Supports Write 1 /Read Burst	Supports Precharge All	Supports Auto- Precharge	Supports Early RAS Precharge
0	0	0	0	1	1	1	0

*2.Checksum for Bytes 0 to 62
This byte is the checksum for bytes 0 through 62. This byte contains the value of the low 8-bits of the arithmetic sum of bytes 0 through 62.

■ BLOCK DIAGRAM



■ ABSOLUTE MAXIMUM RATINGS (See WARNING)

Parameter	Symbol	Va	Unit	
Farameter	Symbol	Min.	Max.	Onit
Supply Voltage*	Vcc	-0.5	+4.6	V
Input Voltage*	Vin	-0.5	+4.6	V
Output Voltage*	Vоит	-0.5	+4.6	V
Storage Temperature	Тѕтс	– 55	+125	°C
Power Dissipation	P _D	_	8.0	W
Output Current (D.C.)	Іоит	-50	+50	mA

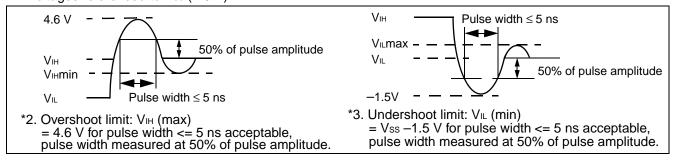
^{*:} Voltages referenced to Vss (= 0 V)

WARNING: Semiconductor devices can be permanently damaged by application of stress (voltage, current, temperature, etc.) in excess of absolute maximum ratings. Do not exceed these ratings.

■ RECOMMENDED OPERATING CONDITIONS

Doromotor	Notes	Symbol		l lmi4		
Parameter	Notes		Min.	Тур.	Max.	Unit
Cupply Voltage	*1	Vcc	3.0	3.3	3.6	V
Supply Voltage	I	Vss	0	0	0	V
Input High Voltage, All Inputs	*1, 2	ViH	2.0	_	Vcc +0.5	V
Input Low Voltage, All Inputs	*1, 3	VIL	-0.5	_	0.8	V
Ambient Temperature		TA	0	_	+70	°C

*1. Voltages referenced to Vss (= 0 V)



WARNING: The recommended operating conditions are required in order to ensure the normal operation of the semiconductor device. All of the device's electrical characteristics are warranted when the device is operated within these ranges.

Always use semiconductor devices within their recommended operating conditionranges. Operation outside these ranges may adversely affect reliability and could result in device failure.

No warranty is made with respect to uses, operating conditions, or combinations not represented on the data sheet. Users considering application outside the listed conditions are advised to contact their FUJITSU representatives beforehand.

■ CAPACITANCE

(Vcc = +3.3 V, f = 1 MHz, T_A = +25°C)

Paramet	or	Symbol	Va	lue	Unit
Faramet	ei	Syllibol	Min.	Max.	Offic
	A ₀ to A ₁₁ , BA ₀ , BA ₁	C _{IN1}	_	59	pF
	RAS, CAS, WE	C _{IN2}		53	pF
	CS₀	Сімз		61	pF
Input Capacitance	CKE ₀	C _{IN4}	_	51	pF
	CLK ₀ , CLK ₁	C _{IN5}	_	35	pF
	DQMB ₀ to DQMB ₇	CIN6	_	18	pF
	SCL	Cscl	_	11	pF
Input/Output Canacitance	SDA	CSDA	_	12	pF
Input/Output Capacitance	DQ ₀ to DQ ₆₃	CDQ		12	pF

■ DC CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.) Notes 1, 2

					Value		
Parameter	Notes	Symbol	Condition	Min.	M	ax.	Unit
				IVIIII.	Std. ver.	Low ver.	
Operating Current (Average Power Supply Current)	*3	Icc1s	Burst: Length = 1 tRC = min for $BL = 1tCK = minOne Bank Active, Outputs OpenAddresses changed up to 1-timeduring tCK (min.)0 \ V \le V_{IN} \le V_{IL} (max.)V_{IH} (min.) \le V_{IN} \le V_{CC}$	_	6	80	mA
		Ісс2Р	CKE = V_{IL} , All Banks Idle tck = min, Power Down Mode $0 \ V \le V_{IN} \le V_{IL}$ (max.) V_{IH} (min.) $\le V_{IN} \le V_{CC}$	_	16	8	mA
Precharge Standby Current (Power *3 Supply Current) *3 Icc2N CK CL 0 V VIH CK NC (ex dui 0 V VIH CC2N CK CL 0 V VIH CC2N CK CL 0 V VIH CK CL 0 V V V V V V V V V V V V V V V V V V V		Icc2PS	CKE = V_{IL} , All Banks Idle CLK = H or L, Power Down Mode 0 V \leq V _{IN} \leq V _{IL} (max.) V _{IH} (min.) \leq V _{IN} \leq V _{CC}	_	8	4	mA
	CKE = V_{IH} , All Banks Idle, t_{CK} = min NOP commands only, Input signals (except to CMD) are changed 1-time during 3 clock cycles $0 \text{ V} \leq V_{IN} \leq V_{IL}$ (max.) V_{IH} (min.) $\leq V_{IN} \leq V_{CC}$	_	80		mA		
		Icc2ns	CKE = V_{IH} , All Banks Idle CLK = H or L, Input signal are stable 0 V \leq V _{IN} \leq V _{IL} (max.) V _{IH} (min.) \leq V _{IN} \leq V _{CC}	_	1	4 80	mA
		Іссзр	CKE = V_{IL} , Any Bank Active tck = min. 0 V \leq V _{IN} \leq V _{IL} (max.) V _{IH} (min.) \leq V _{IN} \leq V _{CC}	_	16	16	mA
Active Standby		Іссзрѕ	CKE = V_{IL} , Any Bank Active CLK = H or L 0 V \leq V _{IN} \leq V _{IL} (max.) V _{IH} (min.) \leq V _{IN} \leq V _{CC}	_	8	4	mA
Active Standby Current (Power Supply Current)	*3	Іссэн	CKE = V_{IH} , Any Bank Active tck = min., NOP commands only, Input signals (except to CMD) are changed 1-time during 3 clock cycles $0 \text{ V} \leq V_{IN} \leq V_{IL}$ (max.) V_{IH} (min.) $\leq V_{IN} \leq V_{CC}$	_	1:	20	mA
		Іссзиѕ	CKE = V _{IH} , Any Bank Active CLK = H or L $0 \text{ V} \le \text{V}_{\text{IN}} \le \text{V}_{\text{IL}} \text{ (max.)}$ V _{IH} (min.) $\le \text{V}_{\text{IN}} \le \text{V}_{\text{CC}}$	_	1	6	mA

(Continued)

(Continued)

					Unit		
Parameter	Notes	es Symbol Condition		Min.		Ma	
				IVIIII.	Std. ver.	Low ver.	
Burst Mode Current (Average Power Supply Current)	*3	Icc4	tck = min, Burst Length = 4 Outputs Open, All Banks Active Gapless Data $0 \ V \le V_{IN} \le V_{IL}$ (max.) V_{IH} (min.) $\le V_{IN} \le V_{CC}$	_	48	30	mA
Auto-refresh Current (Average Power Supply Current)	*3	Icc5	Auto Refresh tck = min trc = min $0 \text{ V} \leq V_{IN} \leq V_{IL} \text{ (max.)}$ Vih (min.) $\leq V_{IN} \leq V_{CC}$	_	13	60	mA
Self-refresh Current (Average Power Supply Current)	*3	Icc6	$eq:continuous_continuous$	_	8	4	mA
Input Leakage Current (All Inputs)		lı (L)	$0 \text{ V} \le V_{IN} \le V_{CC}$ All other pins not under test = 0 V	-30	3	0	μΑ
Output Leakage Currer	nt	lo (L)	$0 \text{ V} \le V_{IN} \le V_{CC}$ Output is disabled (Hi-Z)	-5	Ę	5	μΑ
LVTTL Output High Voltage	*4	Vон	Iон = −2.0 mA	2.4	_	_	V
LVTTL Output Low Voltage	*4	Vol	loL = +2.0 mA	_	0	.4	V

Notes: *1. An initial pause (DESL on NOP) of 200 μs is required after power-on followed by a minimum of eight Auto-refresh cycles.

- *2. DC characteristics is the Serial PD standby state (V_{IN} = V_{SS} or V_{CC}).
- *3. lcc depends on the output termination, load conditions, clock cycle rate and signal clock rate. The specified values are obtained with the output open and no termination register.
- *4. Voltages referenced to Vss = Vssq (= 0 V).

■ AC CHARACTERISTICS

(1) BASE CHARACTERISTICS

(At recommended operating conditions unless otherwise noted.) Notes 1, 2, 3

No.	Parameter Notes	Notes		MB8508S064CH -100/100L		Unit
			Symbol	Min.	Max.	
1	Clock Period	CL = 3	t cкз	10	_	ns
'	Clock Feriod	CL = 2	t ck2	15	_	ns
2	Clock High Time		tсн	3.5	_	ns
3	Clock Low Time		t cL	3.5	_	ns
4	Input Setup Time		t sı	3	_	ns
5	Input Hold Time		tнı	1	_	ns
6	Output Valid from Clock	CL = 3	t _{AC3}	_	8.5	ns
O	(tclk = min)	CL = 2	t _{AC2}		9	113
7	Output in Low-Z *6	}	t LZ	0	_	ns
8	Output in High-Z *6	CL = 3	t HZ3	3	8.5	ns
0	Output in riigh-2	CL = 2	t HZ2	3	9	ns
9	Output Hold Time *6	}	t он	3	_	ns
10	Time between Refresh		t REF	_	65.6	ms
11	Transition Time		tτ	0.5	2	ns
12	CKE Setup Time for Power Down Exit Time)	t cksp	3	_	ns

(2) BASE VALUES FOR CLOCK COUNT/LATENCY

No.	Parameter Notes	Symbol	MB8508 -100/	Unit			
				Min.	Max.		
1	RAS Cycle Time *7		t RC	90	_	ns	
2	RAS Precharge Time		t RP	30	_	ns	
3	RAS Active Time	t RAS	60	110000	ns		
4	RAS to CAS Delay Time *8		t RCD	30	_	ns	
5	Write Recovery Time		twR	10	_	ns	
6	RAS to RAS Bank Active Delay Time		t rrd	20	_	ns	
7	Data-in to Precharge Lead Time		t DPL	10	_	ns	
8	Data-in to Active/Refresh Command Period	CL = 3	t DAL3	2 cyc + t _{RP}	_	ns	
8	Data-in to Active/Refresh Command Period	CL = 2	tDAL2	1 cyc + t _{RP}	_	ns	
9	Mode Register Set Cycle Time		t RSC	20	_	ns	

(3) CLOCK COUNT FORMULA (*9)

$$Clock \ge \frac{Base\ Value}{Clock\ Period}\ (Round\ off\ a\ whole\ number)$$

(4) LATENCY (The latency values on these parameters are fixed regardless of clock period.)

No.	Parameter	Symbol	MB8508S064CH -100/100L	Unit	
1	CKE to Clock Disable			1	Cycle
2	DQM to Output in High-Z		I _{DQZ}	2	Cycle
3	DQM to Input Data Delay		IDQD	0	Cycle
4	Last Output to Write Command Delay			2	Cycle
5	Write Command to Input Data Delay		lowd	0	Cycle
6	Dracharge to Output in High 7 Delev	CL = 3	І конз	3	Cycle
0	Precharge to Output in High-Z Delay	CL = 2	I _{ROH2}	2	Cycle
_	Direct Stan Command to Output in High 7 Delay	CL = 3	Івѕнз	3	Cycle
7	Burst Stop Command to Output in High-Z Delay	CL = 2	I _{BSH2}	2	Cycle
8	CAS to CAS Delay (min)	Iccd	1	Cycle	
9	CAS Bank Delay (min)		Ісво	1	Cycle

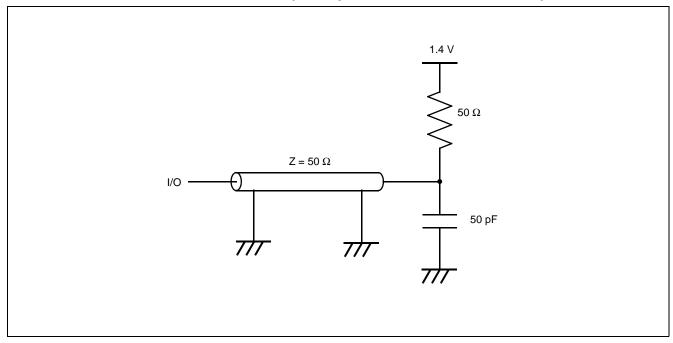
- Notes: *1. An initial pause (DESL on NOP) of 200 μs is required after power-up followed by a minimum of eight Auto-refresh cycles.
 - *2. 1.4 V or VREF is the reference level for measuring timing of signals. Transition times are measured between V_{IH} (min) and V_{IL} (max).
 - *3. AC characteristics assume $t_T = 1$ ns and 50 pF of capacitive load.
 - *4. Maximum value of CL = 2 depends on tck.
 - *5. tac also specifies the access time at burst mode except for first access.
 - *6. Specified where output buffer is no longer driven. toH, t∟z, and tHz define the times at which the output level achieves ±200 mV.
 - *7. Actual clock count of trc (Irc) will be sum of clock count of tras (Iras) and trp (Irp).
 - *8. Operation within the trop (min) ensures that access time is determined by trop (min) + tac (max); if trop is greater than the specified tRCD (min), access time is determined by tAC.
 - *9. All base values are measured from the clock edge at the command input to the clock edge for the next command input.

All clock counts are calculated by a simple formula:

clock count equals base value divided by clock period (round off to a whole number).

^{*}Source: See MB81F64842C Data Sheet for details on the electrical.

■ AC OPERATING TEST CONDITION (Example of AC Test Load Circuit)



■ SERIAL PRESENCE DETECT(SPD) FUNCTION

1. PIN DESCRIPTIONS

SCL (Serial Clock)

SCL input is used to clock all data input/output of SPD

SDA (Serial Data)

SDA is a common pin used for all data input/output of SPD. The SDA pull-up resistor is required due to the open-drain output.

SA₀, SA₁, SA₂ (Address)

Address inputs are used to set the least significant three bits of the eight bits slave address. The address inputs must be fixed to select a particular module and the fixed address of each module must be different each other. For this module, any address inputs are not required because all addresses (SA₀, SA₁, SA₂) are driven to Vss on the module.

2. SPD OPERATIONS

CLOCK and DATA CONVENTION

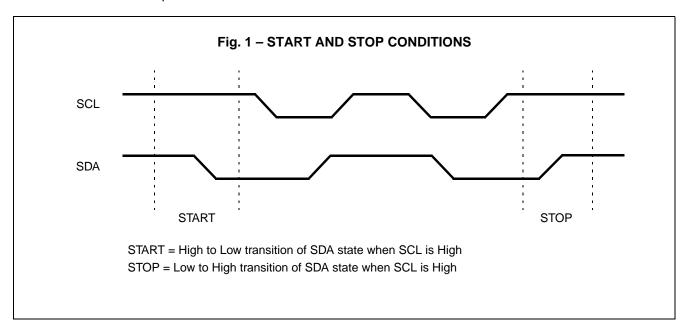
Data states on the SDA can change only during SCL = Low. SDA state changes during SCL = High are indicated start and stop conditions. Refer to Fig. 1 below.

START CONDITION

All commands are preceded by a start condition, which is a transition of SDA state from High to Low when SCL = High. SPD will not respond to any command until this condition has been met.

STOP CONDITION

All read or write operation must be terminated by a stop condition, which is a transition of SDA state from Low to High when SCL = High. The stop condition is also used to make the SPD into the state of standby power mode after a read sequence.



ACKNOWLEDGE

Acknowledge is a software convention used to indicate successful data transfer. The transmitting device, either master or slave, will release the bus after transmitting eight bits. During the ninth clock cycle the receiver will put the SDA line to Low in order to acknowledge that it received the eight bits of data.

The SPD will respond with an acknowledge when it received the start condition followed by slave address issued by master.

In the read operation, the SPD will transmit eight bits of data, release the SDA line and monitor the line for an acknowledge. If an acknowledge is detected and no stop condition is issued by master, the SPD will continue to transmit data. If an acknowledge is not detected, the SPD will terminated further data transmissions. The master must then issue a stop condition to return the SPD to the standby power mode.

In the write operation, upon receipt of eight bits of data the SPD will respond with an acknowledge, and await the next eight bits of data, again responding with an acknowledge until the stop condition is issued by master.

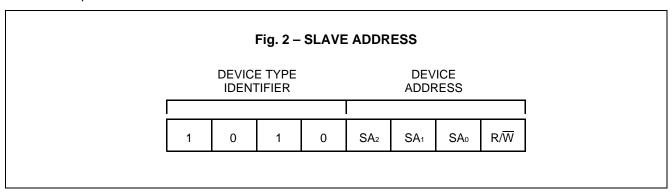
SLAVE ADDRESS ADDRESSING

Following a start condition, the master must output the eight bits slave address. The most significant four bits of the slave address are device type identifier. For the SPD this is fixed as 1010[B]. Refer to the Fig. 2 below.

The next three significant bits are used to select a particular device. A system could have up to eight SPD devices —namely up to eight modules— on the bus. The eight addresses for eight SPD devices are defined by the state of the SA₀, SA₁ and SA₂ inputs. For this module, the three bits are fixed as 000[B] because all addresses are driven to Vss on the module. Therefore, no address inputs are required.

The last bit of the slave address defines the operation to be performed. When R/\overline{W} bit is "1", a read operation is selected, when R/\overline{W} bit is "0", a write operation is selected.

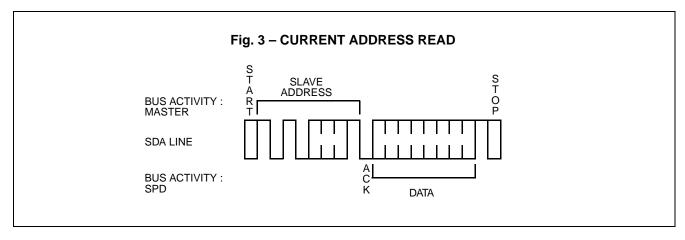
Following the start condition, the SPD monitors the SDA line comparing the slave address being transmitted with its slave address (device type and state of SA_0 , SA_1 , and SA_2 inputs). Upon a correct compare the SPD outputs an acknowledge on the SDA line. Depending on the state of the R/\overline{W} bit, the SPD will execute a read or write operation.



3. READ OPERATIONS

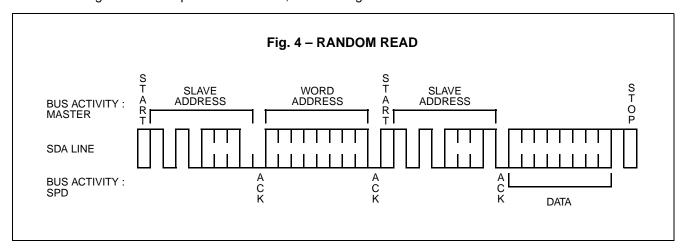
CURRENT ADDRESS READ

Internally the SPD contains an address counter that maintains the address of the last data accessed, incremented by one. Therefore, if the last access (either a read or write operation) was to address(n), the next read operation would access data from address(n+1). Upon receipt of the slave address with the R/\overline{W} bit = "1", the SPD issues an acknowledge and transmits the eight bits of data during the next eight clock cycles. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 3 for the sequence of address, acknowledge and data transfer.



RANDOM READ

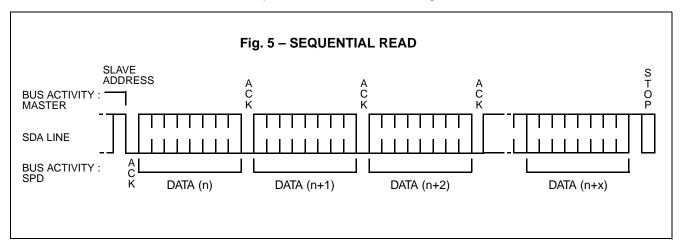
Random Read operations allow the master to access any memory location in a random manner. Prior to issuing the slave address with the R/\overline{W} bit = "1", the master must first perform a "dummy" write operation on the SPD. The master issues the start condition, and the slave address followed by the word address. After the word address acknowledge, the master immediately reissues the start condition and the slave address with the R/\overline{W} bit = "1". This will be followed by an acknowledge from the SPD and then by the eight bits of data. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 4 for the sequence of address, acknowledge and data transfer.



SEQUENTIAL READ

Sequential Read can be initiated as either a current address read or random read. The first data are transmitted as with the other read mode, however, the master now responds with an acknowledge, indicating it requires additional data. The SPD continues to output data for each acknowledge received. The master terminates this transmission by issuing a stop condition, omitting the ninth clock cycle acknowledge. Refer to Fig. 5 for the sequence of address, acknowledge and data transfer.

The data output is sequential, with the data from address(n) followed by the data from address(n+1). The address counter for read operations increments all address bits, allowing the entire memory contents to be serially read during one operation. At the end of the address space (address 255), the counter "rolls over" to address0 and the SPD continues to output data for each acknowledge received.



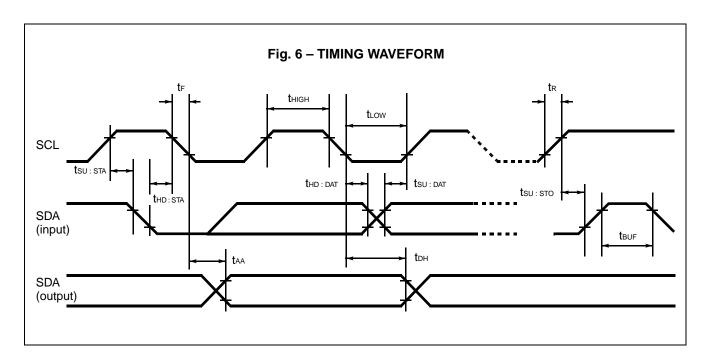
4. DC CHARACTERISTICS

Parameter	Note	Symbol	Condition	Va	Unit	
Parameter				Min.	Max.	Offic
Input Leakage Current		Sılı	$0 \text{ V} \leq V_{IN} \leq V_{CC}$	-10	10	μΑ
Output Leakage Current		SILO	0 V ≤ Vouт ≤ Vcc	-10	10	μΑ
Output Low Voltage	*1	Svol	IoL = 3.0 mA	_	0.4	V

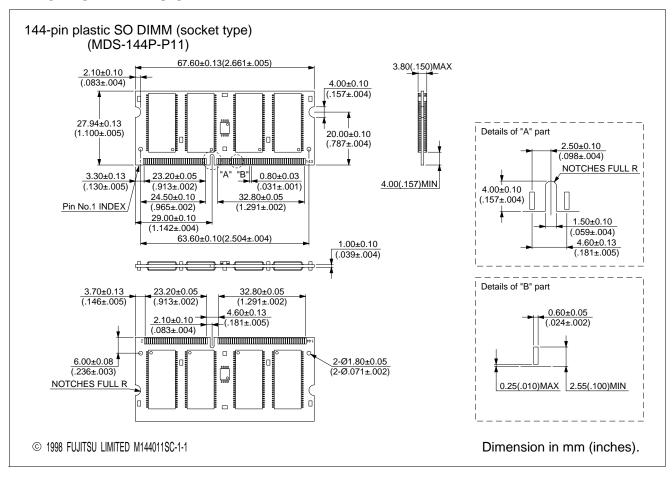
Note: *1. Referenced to Vss.

5. AC CHARACTERISTICS

No.	Parameter	Sumb al	Value		1 lm:4
		Symbol	Min.	Max.	Unit
1	SCL Clock Frequency	fscL	_	100	KHz
2	Noise Suppression Time Constant at SCL, SDA Inputs	Tı	_	100	ns
3	SCL Low to SDA Data Out Valid	t AA	_	3.5	μs
4	Time the Bus Must Be Free Before a New Transmission Can Start	t BUF	4.7	_	μs
5	Start Condition Hold Time	t hd:sta	4.0	_	μs
6	Clock Low Period	t LOW	4.7	_	μs
7	Clock High Period	t HIGH	4.0	_	μs
8	Start Condition Setup Time	tsu:sta	4.7	_	μs
9	Data in Hold Time	thd:dat	0	_	μs
10	Data in Setup Time	tsu:dat	250	_	ns
11	SDA and SCL Rise Time	t _R	_	1	μs
12	SDA and SCL Fall Time	t⊧	_	300	ns
13	Stop Condition Setup Time	tsu:sto	4.7	_	μs
14	Data Out Hold Time	tон	100	_	ns
15	Write Cycle Time	t wr	_	15	ms



■ PACKAGE DIMENSION



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